

## N-channel 600 V, 0.53 $\Omega$ typ., 10 A MDmesh™ II Power MOSFET in I<sup>2</sup>PAK package

Datasheet - obsolete product

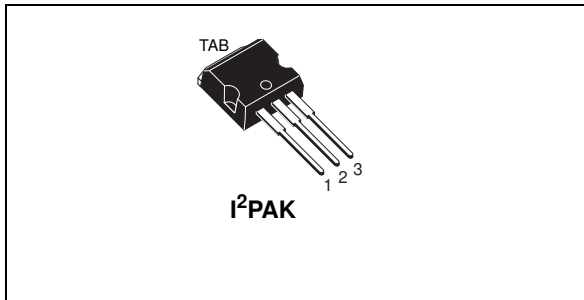
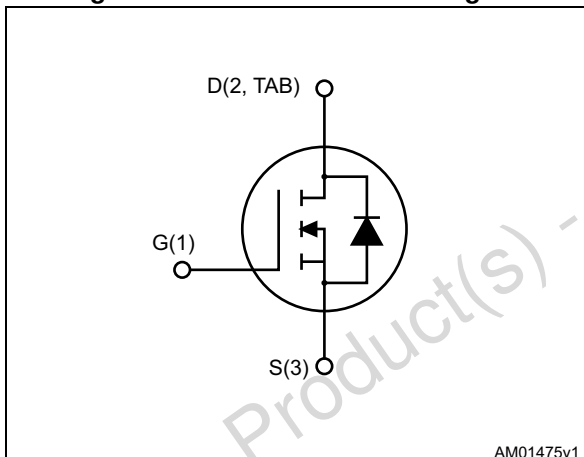


Figure 1. Internal schematic diagram



### Features

Order code	$V_{DS}$ @ $T_{J,max}$	$R_{DS(on)}$ max.	$I_D$	$P_{TOT}$
STI10NM60N	650 V	< 0.53 $\Omega$	10 A	70 W

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

Order code	Marking	Package	Packing
STI10NM60N	10NM60N	I <sup>2</sup> PAK	Tube

# Contents

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Obsolete Product(s) - Obsolete Product(s)



# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	
		I <sup>2</sup> PAK	Unit
V <sub>GS</sub>	Gate- source voltage	± 25	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	10	A
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100 °C	5	A
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	32	A
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	70	W
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	15	V/ns
V <sub>ISO</sub>	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s; T <sub>C</sub> = 25 °C)		V
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	- 55 to 150	°C

1. Pulse width limited by safe operating area.

2. I<sub>SD</sub> ≤ 10 A, di/dt ≤ 400 A/μs, V<sub>DS peak</sub> ≤ V<sub>(BR)DSS</sub>, V<sub>DD</sub> = 80% V<sub>(BR)DSS</sub>.

**Table 3. Thermal data**

Symbol	Parameter	Value	
		I <sup>2</sup> PAK	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max.	1.79	°C/W
R <sub>thj-amb</sub>	Thermal resistance junction-ambient max.	62.50	°C/W
R <sub>thj-pcb</sub>	Thermal resistance junction-pcb max.		°C/W

**Table 4. Avalanche characteristics**

Symbol	Parameter	Value	Unit
I <sub>AS</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by T <sub>J</sub> max.)	4	A
E <sub>AS</sub>	Single pulse avalanche energy (starting T <sub>J</sub> = 25 °C, I <sub>D</sub> = I <sub>AS</sub> , V <sub>DD</sub> = 50 V)	200	mJ

## 2 Electrical characteristics

( $T_{\text{case}} = 25\text{ °C}$  unless otherwise specified)

**Table 5. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1\text{ mA}$ , $V_{GS} = 0$ $I_D = 1\text{ mA}$ , $V_{GS} = 0$ , $T_C = 150\text{ °C}$	600	650		V
$I_{DSS}$	Zero-gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 600\text{ V}$ $V_{DS} = 600\text{ V}$ , $T_C = 125\text{ °C}$			1 100	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 25\text{ V}$			$\pm 100$	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$	2	3	4	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$ , $I_D = 4\text{ A}$		0.53	0.55	$\Omega$

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 50\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0$	-	540	-	pF
$C_{oss}$	Output capacitance		-	44	-	pF
$C_{riss}$	Reverse transfer capacitance		-	1.2	-	pF
$C_{oss\text{ eq}}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0\text{ to }480\text{ V}$ , $V_{GS} = 0$	-	110	-	pF
$R_g$	Gate input resistance	$f = 1\text{ MHz}$ open drain	-	6	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480\text{ V}$ , $I_D = 8\text{ A}$ , $V_{GS} = 10\text{ V}$	-	19	-	nC
$Q_{gs}$	Gate-source charge		-	3	-	nC
$Q_{gd}$	Gate-drain charge		-	10	-	nC

1.  $C_{oss\text{ eq}}$  time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300\text{ V}$ , $I_D = 4\text{ A}$ , $R_G = 4.7\ \Omega$ , $V_{GS} = 10\text{ V}$	-	10	-	ns
$t_r$	Rise time		-	12	-	ns
$t_{d(off)}$	Turn-off-delay time		-	32	-	ns
$t_f$	Fall time		-	15	-	ns

Table 8. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		8	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				32	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 8\text{ A}$ , $V_{GS} = 0$	-		1.3	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 8\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$	-	250		ns
$Q_{rr}$	Reverse recovery charge		-	2.12		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current				17	A
$t_{rr}$	Reverse recovery time	$I_{SD} = 8\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$ $T_J = 150\text{ }^\circ\text{C}$	-	315		ns
$Q_{rr}$	Reverse recovery charge				2.6	$\mu\text{C}$
$I_{RRM}$	Reverse recovery current				16.5	A

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for I<sup>2</sup>PAK

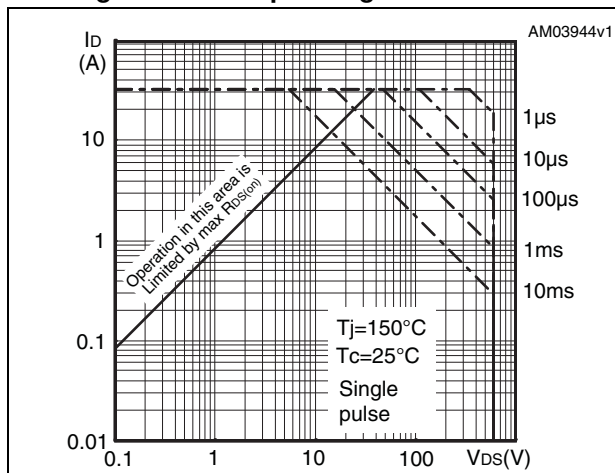


Figure 3. Thermal impedance for I<sup>2</sup>PAK

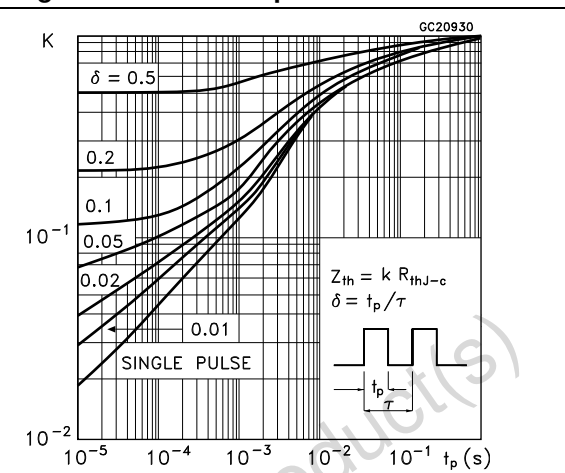


Figure 4. Output characteristics

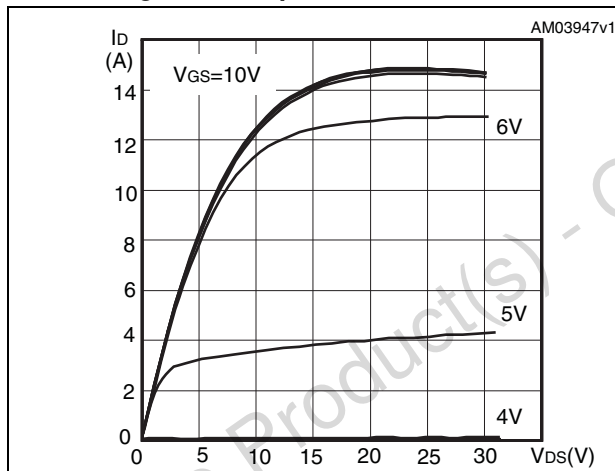


Figure 5. Transfer characteristics

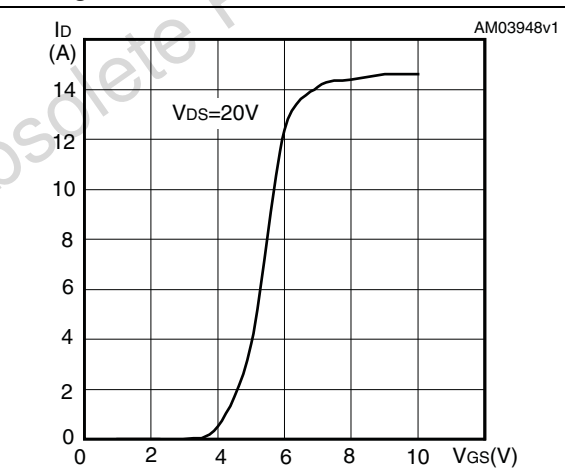


Figure 6. Normalized V<sub>DS</sub> vs. temperature

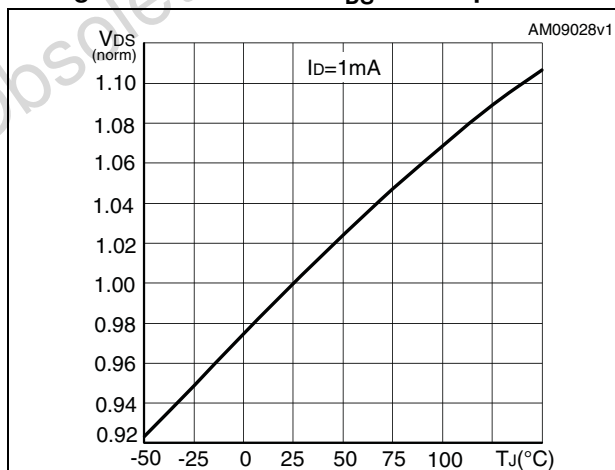


Figure 7. Static drain-source on-resistance

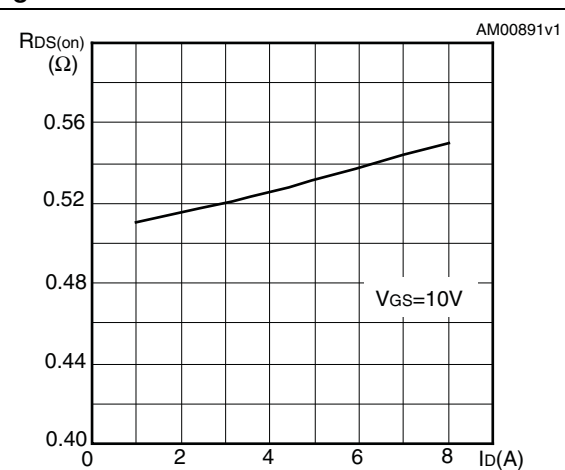


Figure 8. Gate charge vs. gate-source voltage

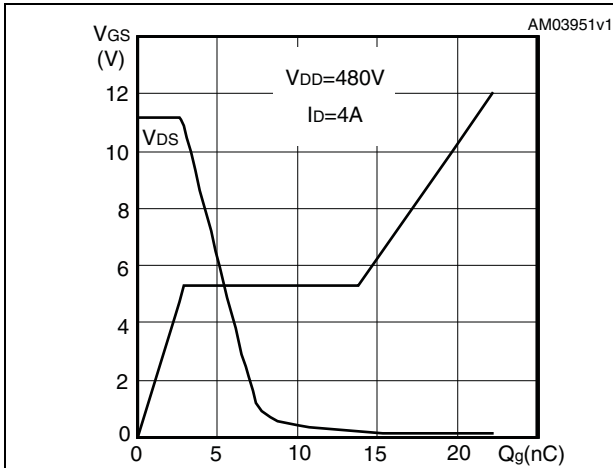


Figure 9. Capacitance variations

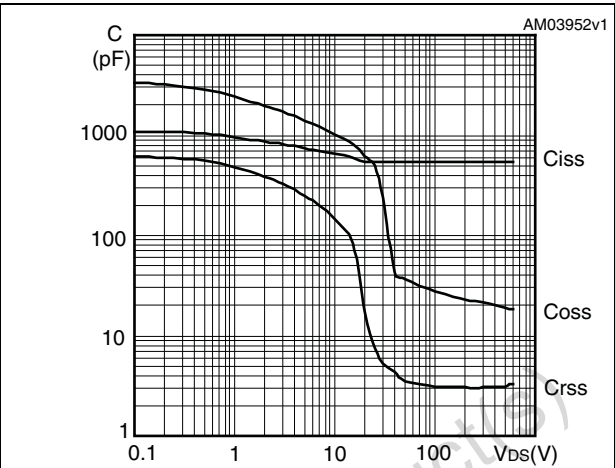


Figure 10. Normalized gate threshold voltage vs. temperature

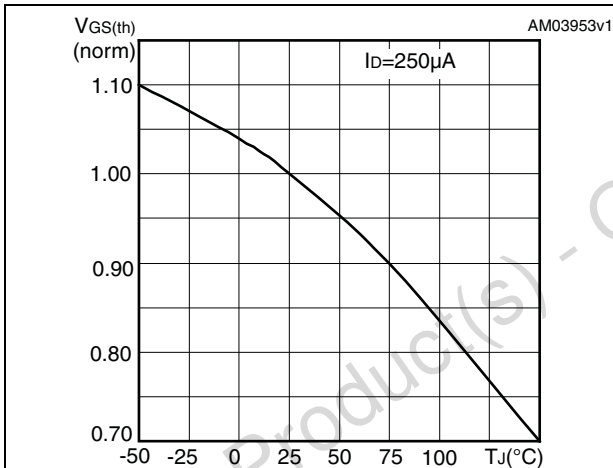
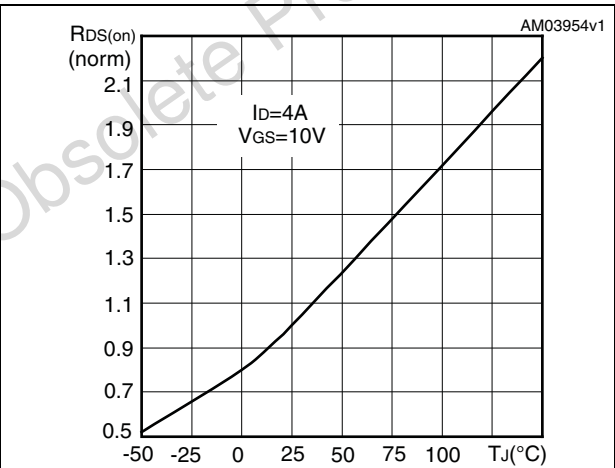
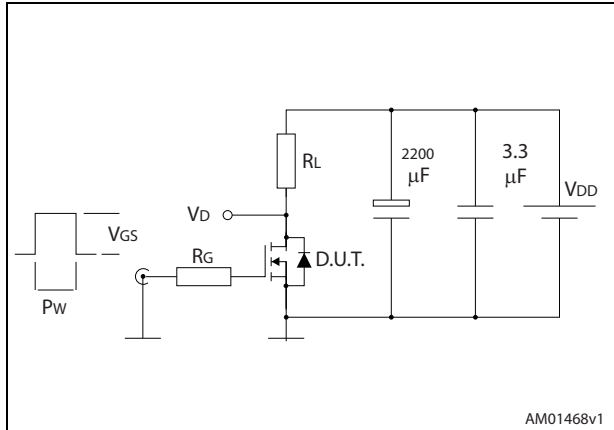


Figure 11. Normalized on-resistance vs. temperature



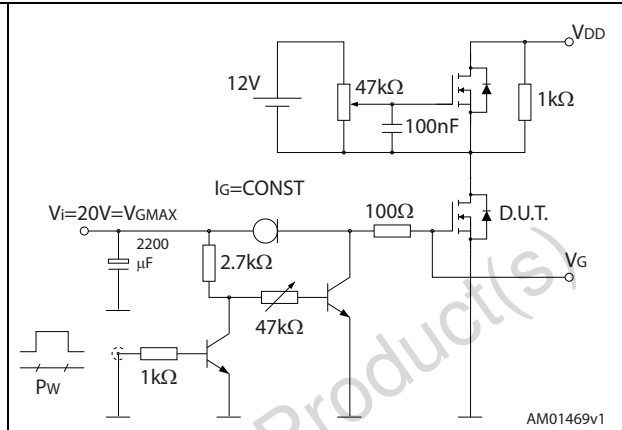
### 3 Test circuits

Figure 12. Switching times test circuit for resistive load



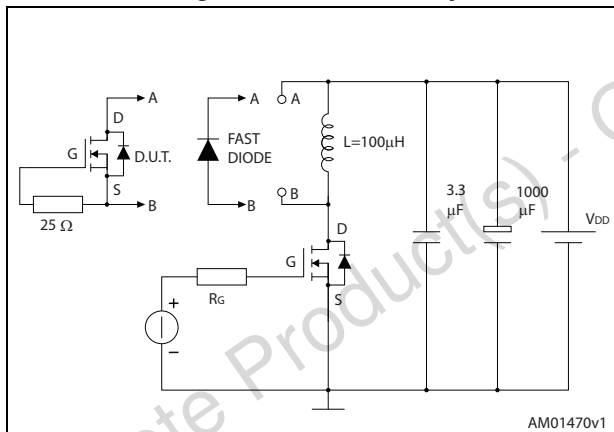
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Figure 13. Gate charge test circuit



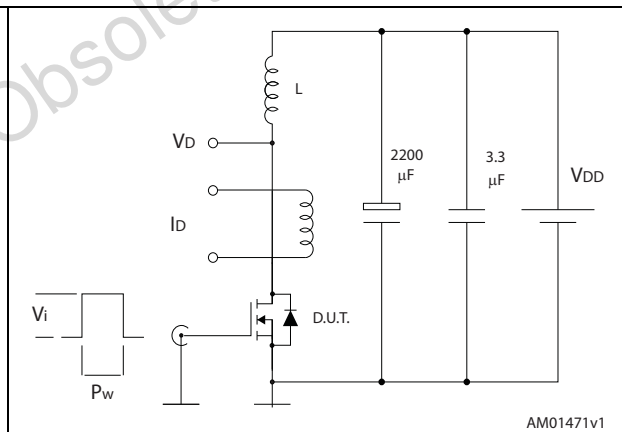
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Figure 14. Test circuit for inductive load switching and diode recovery times



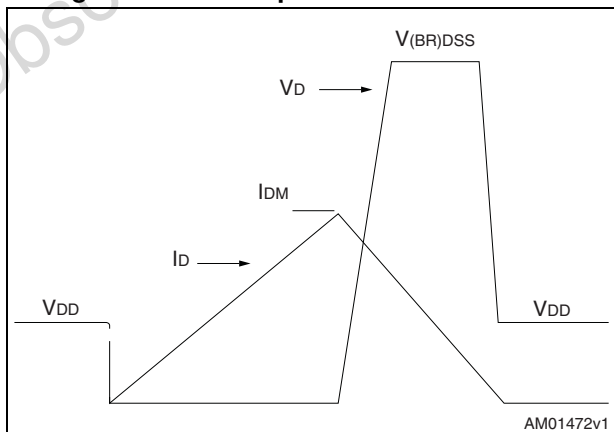
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Figure 15. Unclamped inductive load test circuit



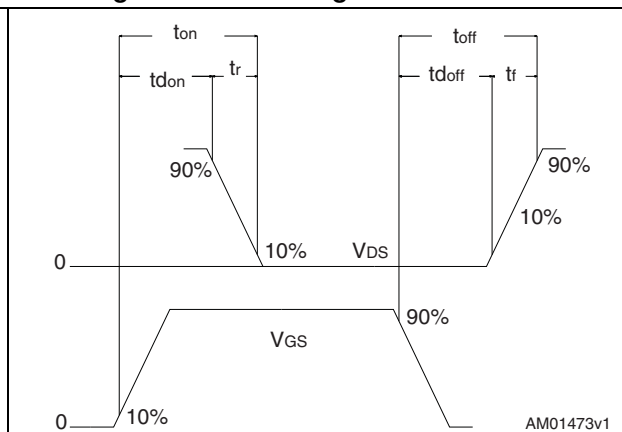
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Figure 16. Unclamped inductive waveform



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Figure 17. Switching time waveform



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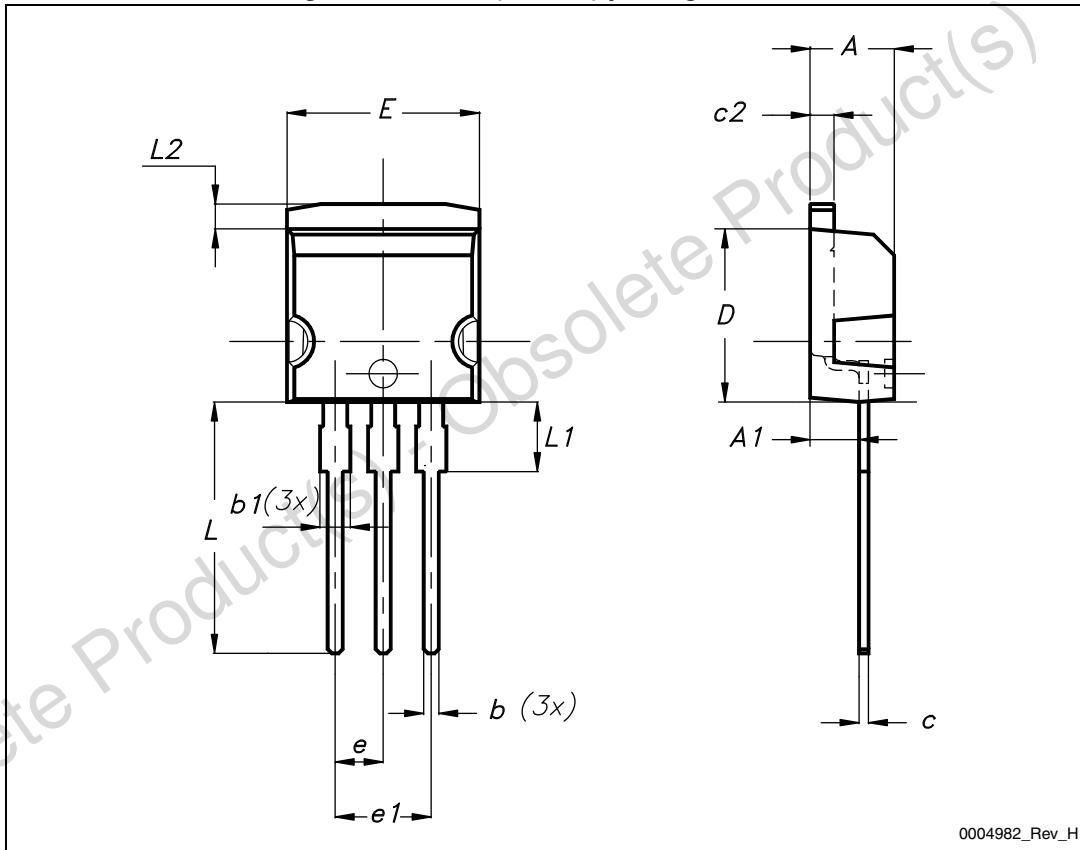


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 I<sup>2</sup>PAK package information

Figure 18. I<sup>2</sup>PAK (TO-262) package outline



0004982\_Rev\_H

Table 9. I<sup>2</sup>PAK (TO-262) package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	2.40		2.72
b	0.61		0.88
b1	1.14		1.70
c	0.49		0.70
c2	1.23		1.32
D	8.95		9.35
e	2.40		2.70
e1	4.95		5.15
E	10		10.40
L	13		14
L1	3.50		3.93
L2	1.27		1.40

## 5 Revision history

**Table 10. Document revision history**

Date	Revision	Changes
10-Jun-2009	1	First release
12-Jan-2010	2	Figure 4: Safe operating area for TO-220FP has been corrected
31-Mar-2010	3	Features have been corrected
17-Sep-2010	4	Content reworked to improve readability
24-Nov-2010	5	Corrected $I_D$ value
16-Nov-2012	6	Inserted new package and mechanical data: I <sup>2</sup> PAK
18-Jul-2013	7	Updated Section 4: Package mechanical data. Minor text changes.
02-Dec-2015	8	Part numbers STD10NM60N, STF10NM60N, STP10NM60N, STU10NM60N have been moved to a separate datasheet.

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